

Abstracts

Investigation of Tapered Multiple Microstrip Lines for VLSI Circuits (1988 Vol. I [MWSYM])

M.A. Mehalic, C.H. Chan and R. Mittra. "Investigation of Tapered Multiple Microstrip Lines for VLSI Circuits (1988 Vol. I [MWSYM])." 1988 MTT-S International Microwave Symposium Digest 88.1 (1988 Vol. I [MWSYM]): 215-218.

The S-parameters of coupled, tapered microstrip etches are calculated as a function of frequency using an iteration-perturbation technique. The propagation constants and impedance matrices are computed using a perturbation-iteration approach. Representative results are obtained to illustrate the application of the method.

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